

DA-TEST EXPANDS IC TEST CAPABILITY

PARTNERSHIP WITH INOVYS CORPORATION FEATURING INOVYS OCELOT DFT-FOCUSED TEST PLATFORM

Canada's first and only Test House provides local access to ATE equipment and Test Engineering resources to the thriving Fabless Semiconductor community in the Eastern Canada region.

Ottawa, Ontario, August 15, 2003 – DA-Test Incorporated, a full-service test house, announced today the installation of the Inovys Ocelot Test Platform in its facility located at 700 Palladium Drive near the Corel Center in Kanata. The new tester compliments existing DA-Test capability, addressing Integrated Circuit (IC) products designed with specialized self-test features.

This is the fourth major partnership DA-Test has entered into, underscoring the strength and global recognition of the Fabless Semiconductor industry in the Southeastern Ontario and West Quebec region. Started in early 2002, DA-Test has established itself as an important element of the local Fabless IC industry by providing IC Test Development and Specialized IC Production Test services to a large number of local and international customers.

Pat DiPietro of VenGrowth Capital Partners Inc. comments, “Access to ATE Test Equipment and Test Engineering resources is critical to this subcontracting-oriented industry. Having a test house located right here in Ottawa enables our local companies to better compete on the global stage. It is exciting to see DA-Test flourish and continue to add capability, in this case a very interesting new type of tester that is a good match for quite few companies in this region”.

“There is currently a discontinuity in the IC Production Test industry. Integrated Circuit performance and complexity is driving the required capability of traditional production test systems in a direction that is out of synch with production test cost requirements” said Sam Ho, Founder and President of DA-Test. “A new paradigm with production equipment specifically designed to test high performance IC devices incorporating self-test techniques has been in development for several years. Inovys is first to address this new market with a system that enhances the advantages of this approach, simultaneously satisfying our customer’s performance and cost requirements”.

CEO Paul Sakamoto is one of the ATE industry veterans leading Inovys. “Inovys has the only practical solution for direct execution of STIL based test patterns and for dramatically reducing high volume production test costs. Device complexity and performance is running away from conventional test capabilities, and the only solution for keeping pace is Design For Test (DFT). Complete integration between EDA



(Electronic Design Automation) and test solutions is now a necessity”.

“We founded Inovys in 1999 to develop practical, economic, and scalable solutions for the semiconductor industry’s move to DFT. Our advanced test system and software technologies provide the fastest test development with the lowest test cost, while our ability to communicate fault data directly back to EDA gives our systems the ability to report gate level fault information. The most complex semiconductor chips are tested more completely, quickly, and economically with Inovys and DFT approach”.

“Our strategy of approaching test from the design side fits perfectly with the engineering services model of DA-Test. DA-Test counsels its customers in all aspects of test right from the beginning of design through to production. The full life cycle partnership that DA-Test has established with the Canadian Fabless Semiconductor Companies gives us a unique opportunity to partner with a company that echoes our full service model”.

About Inovys and the Ocelot DFT-Focused IC Tester

Inovys, www.inovys.com

Ocelot takes advantage of on-chip design-for-test (DFT) structures such as scan chains to test the gamut of logic ICs, ranging from low-cost consumer devices to complex digital SOCs and microprocessors. A production-floor version provides up to 1536 signal pins to handle high-I/O-count SOC devices or to test more than 32 low-pin-count devices in parallel. A desktop version supports 256 pins. Both can apply scan data rates to 50 MHz. The vendor's operating system uses the IEEE 1450 Standard Test Interface Language (STIL) to link to commercial automatic-test-pattern-generation (ATPG) products, and it can link failure information back to ATPG diagnostic tools for gate-level diagnosis of device defects.

Inovys is a privately held US corporation with head office located in Pleasanton, California. Inovys partners include; Advantest, InTest, Mentor Graphics, Synopsys and LogicVision.

About DA-Test

DA-Test, www.da-test.com

Incorporated on January 17, 2002, DA-Test is the first full-service test house serving the fabless semiconductor community in the Ottawa, Canada region. DA-Test provides a full range of ATE related services including; test program development, product characterization and access to leading-edge ATE equipment and data analysis software.

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